

BQ24392-Q1 支持 USB 电池充电规范版本 1.2 检测功能的双路 SPST USB 2.0 高速开关

1 特性

- 汽车电子 应用认证
- 具有符合 AEC-Q100 的下列结果：
 - 器件温度 1 级：-40°C 至 125°C 的环境运行温度范围
 - 器件人体模型 (HBM) 静电放电 (ESD) 分类等级 2
 - 器件组件充电模式 (CDM) ESD 分类等级 C4B
- USB 2.0 高速开关
- 检测符合 USB 电池充电规范版本 1.2 (BCv1.2) 的充电器
- 兼容附件
 - 专用充电端口
 - 标准下行端口
 - 充电下行端口
- 非标准充电器
 - Apple™ 充电器
 - TomTom™ 充电器
 - 不符合 USB 电池充电规范版本 1.2 (BCv1.2) 的 USB 充电器
- -2V 至 28V VBUS 电压范围
- 静电放电 (ESD) 性能经测试符合 JESD 22 规范
 - 4000V 人体放电模式
 - 1500V 组件充电模式 (C101)
- 至接地 (GND) 的 ESD 性能 DP_CON/DM_CON
 - ±8kV 接触放电 (IEC 61000-4-2)

2 应用

- 后座娱乐系统
- GPS 系统

3 说明

BQ24392-Q1 是一款具有充电器检测功能的双路单刀单掷 (SPST) USB 2.0 高速隔离开关，可与 micro-USB 和 mini-USB 端口搭配使用。凭借这款 USB 开关，移动电话、平板电脑和其它电池供电型电子设备可通过不同适配器充电，并且系统软件需求最低。该器件的充电器检测电路可支持符合 USB 电池充电规范版本 1.2 (BCv1.2) 的 Apple™、TomTom™ 以及其它非标准充电器。

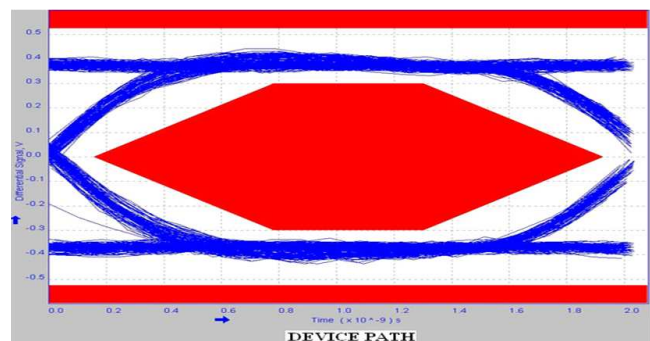
当 micro-USB 或 mini-USB 端口连接充电器时，BQ24392-Q1 器件由 VBUS 供电，可承受 28V 电压，无需外部保护。

器件信息⁽¹⁾

| 器件型号 | 封装 | 封装尺寸 (标称值) |
|------------|-----------|-----------------|
| BQ24392-Q1 | UQFN (10) | 2.05mm x 1.55mm |

(1) 如需了解所有可用封装，请见数据表末尾的可订购产品附录。

USB 开关的 480Mbps USB 2.0 眼图



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4 修订历史记录

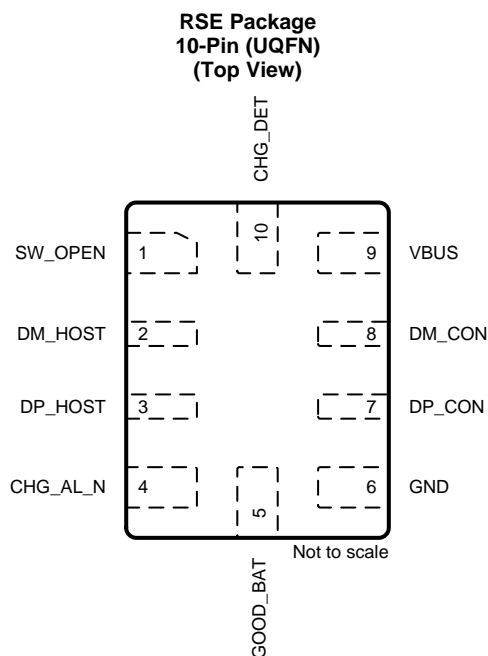
| Changes from Revision C (January 2016) to Revision D | Page |
|--|------|
| • 从 BQ24932-Q1 更改为 BQ24392-Q1 说明 | 1 |
| • Moved the Storage temperature range to the <i>Absolute Maximum Ratings</i> table. | 4 |
| • Changed Handling Ratings To: <i>ESD Ratings</i> | 4 |
| • Changed From: BQ24932-Q1 To: BQ24392-Q1 in the <i>Overview</i> | 7 |
| • Changed title From: <i>Using the BQ24932 GPIOs</i> To: <i>Using the BQ24392-Q1 GPIOs</i> | 10 |

| Changes from Revision B (January 2015) to Revision C | Page |
|---|------|
| • Changed diode direction from left facing to right facing in <i>Application Schematic</i> | 11 |

| Changes from Revision A (September 2014) to Revision B | Page |
|--|------|
| • 更新了“特性”中的“安全及管理批准”列表 | 1 |

| Changes from Original (August 2014) to Revision A | Page |
|---|------|
| • 最初发布的完整版文档 | 1 |

5 Pin Configuration and Functions



Pin Functions

| PIN | | I/O | DESCRIPTION |
|-----|----------|-----|---|
| NO. | NAME | | |
| 1 | SW_OPEN | O | USB switch status indicator Open-drain output. 10 kΩ external pull-up resistor required SW_OPEN = LOW indicates when switch is connected SW_OPEN = HIGH-Z indicates when switch is not connected |
| 2 | DM_HOST | I/O | D ⁻ signal to transceiver |
| 3 | DP_HOST | I/O | D ⁺ signal to transceiver |
| 4 | CHG_AL_N | O | Charging status indicator Open-drain output. 10 kΩ external pull-up resistor required. CHG_AL_N = LOW indicates when charging allowed CHG_AL_N = HIGH-Z indicates when charging is not allowed |
| 5 | GOOD_BAT | I | Battery status indication from system This pin indicates the status of the battery GOOD_BAT = LOW indicates a dead battery GOOD_BAT = HIGH indicates a good battery |
| 6 | GND | – | Not internally connected |
| 7 | DP_CON | I/O | D ⁺ signal from USB connector |
| 8 | DM_CON | I/O | D ⁻ signal from USB connector |
| 9 | VBUS | I | Supply pin from USB connector |
| 10 | CHG_DET | O | Charger detection indicator Push-pull output to the system CHG_DET = LOW indicates when a charger is not detected CHG_DET = HIGH indicates when a charger detected |

6 Specifications

6.1 Absolute Maximum Ratings

 over -40°C to 125°C temperature range (unless otherwise noted)

| | | MIN | MAX | UNIT |
|------------------|---------------------------|------|-----|--------------------|
| Input Voltage | VBUS | -2 | 28 | V |
| | CHG_AL_N | -2 | 28 | |
| | DM_HOST | -0.3 | 7 | |
| | DP_HOST | -0.3 | 7 | |
| | GOOD_BAT | -0.3 | 7 | |
| | DP_CON | -0.3 | 7 | |
| | DM_CON | -0.3 | 7 | |
| | CHG_DET | -0.3 | 7 | |
| T _{stg} | Storage temperature range | -65 | 150 | $^{\circ}\text{C}$ |

6.2 ESD Ratings

| | | | | VALUE | UNIT |
|--------------------|-------------------------|---|--|-------|------|
| V _(ESD) | Electrostatic discharge | Human body model (HBM), per AEC Q100-002 ⁽¹⁾ | | ±4000 | V |
| | | Charged device model (CDM), per AEC Q100-011 | Corner pins (DP_CON and DM_CON to GND) | ±8000 | |
| | | | Other pins | ±1500 | |

(1) AEC Q100-002 indicates HBM stressing is done in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

| | | MIN | MAX | UNIT |
|----------|--|------|------|------|
| VBUS | | 4.75 | 5.25 | V |
| GOOD_BAT | | 0 | VBUS | |
| DM_HOST | | 0 | 3.6 | |
| DP_HOST | | 0 | 3.6 | |
| DM_CON | | 0 | 3.6 | |
| DP_CON | | 0 | 3.6 | |

6.4 Thermal Information

| THERMAL METRIC ⁽¹⁾ | | BQ24392-Q1 | UNIT |
|-------------------------------|--|------------|------|
| | | RSE | |
| | | 10 PINS | |
| R _{θJA} | Junction-to-ambient thermal resistance | 167.7 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | 78.8 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | 95.8 | °C/W |
| ψ _{JT} | Junction-to-top characterization parameter | 4.7 | °C/W |
| ψ _{JB} | Junction-to-board characterization parameter | 95.9 | v |

 (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

 $V_{BUS} = 4.5\text{ V to }5.5\text{ V}$, $T_A = -40^\circ\text{C to }125^\circ\text{C}$ (unless otherwise noted)

| PARAMETER | | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------------|--|----------------------------------|---|-------|---------------------|-----|------|
| V _{BUS_VALID} | VBUS Valid threshold | | Rising VBUS threshold | 3.5 | | | V |
| V _{OH} | CHG_DET | CHG_DET | I _{OH} = −2 mA | 3.5 | VBUS ⁽¹⁾ | | V |
| V _{OL} | CHG_DET, SW_OPEN, CHG_AL_N | CHG_DET, SW_OPEN, CHG_AL_N | I _{OL} = 2 mA | 0.4 | | | V |
| V _{IH} | High-level input voltage | GOOD_BAT | | 1.1 | | | V |
| V _{IL} | Low-level input voltage | | | 0.5 | | | V |
| R _{PD} | Internal pull-down resistance | | | 950 | | | kΩ |
| t _{DBP} | Dead battery provision timer | | | 32 | 45 | | Mins |
| V _{USBIO} | Analog signal range | DM_CON, DP_CON, DM_HOST, DP_HOST | | 0 | 3.6 | | V |
| R _{ON} | ON-state resistance | | V _{DM_HOST} and V _{DP_HOST} = 0 to 3.6 V, I _{DP_CON} and I _{DM_CON} = −2 mA | 6 | 8 | | Ω |
| R _{ON(flat)} | ON-state resistance flatness | | | 1.1 | 2.4 | | Ω |
| ΔR _{ON} | ON- state resistance match between channels | | V _{DM_HOST} and V _{DP_HOS} T = 0.4 V, I _{DP_CON} and I _{DM_CON} = −2 mA | 0.5 | | | Ω |
| I _{CC-SW (ON)} | Current consumption | | V _{VBUS} = 5 V, USB Switch ON; V _{IH(GOOD_BAT)} = 1.1 V | 250 | 350 | | μA |
| | | | V _{VBUS} = 5 V, USB Switch ON; V _{IH(GOOD_BAT)} = 2.5 V | 80 | 115 | | μA |
| I _{CC-SW (OFF)} | Current consumption with USB switch off | | V _{VBUS} = 5 V; USB Switch OFF | 45 | 75 | | μA |
| I _{USBIO (ON)} | Output port leakage current with USB switch on | | V _I = OPEN, V _O = 0.3 V or 2.7 V, Switch ON | 50 | 90 | | nA |
| I _{USBIO (OFF)} | Leakage current with USB switch off | | V _I = 0.3 V, V _O = 2.7 V or V _I = 2.7 V, V _O = 0.3 V, Switch OFF | 45 | 75 | | nA |
| C _{I(OFF)} | Capacitance with USB switch off | DP_HOST, DM_HOST | DC bias = 0 V or 3.6 V, f = 10 MHz, Switch OFF | 2 | | | pF |
| C _{O(OFF)} | Capacitance with USB switch off | DP_CON, DM_CON | | 10 | | | pF |
| C _{I(ON)} | Capacitance with USB switch on | DP_HOST, DM_HOST | DC bias = 0 V or 3.6 V, f = 10 MHz, Switch ON | 11 | | | pF |
| C _{O(ON)} | Capacitance with USB switch on | DP_CON, DM_CON | | 11 | | | pF |
| BW | Bandwidth | | R _L = 50 Ω, Switch ON | 1 | | | GHz |
| O _{ISO} | Isolation with USB switch off | | f = 240 MHz, R _L = 50 Ω, Switch OFF | −26 | | | dB |
| X _{TALK} | Crosstalk | | f = 240 MHz, R _L = 50 Ω | −30.5 | | | dB |

(1) CHG_DET max value will be clamped at 7 V when $V_{VBUS} > 7\text{ V}$

6.6 Typical Characteristics

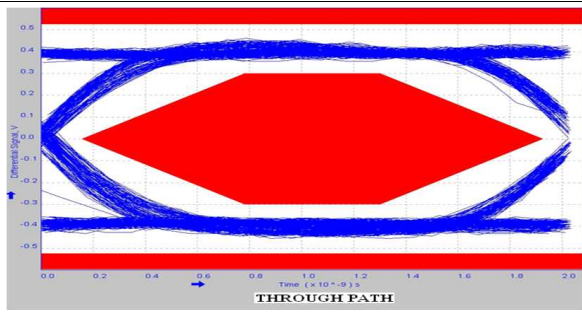


Figure 1. 480-Mbps USB 2.0 Eye Diagram with No Device

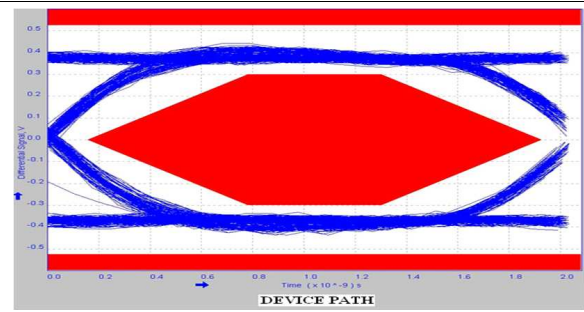


Figure 2. 480-Mbps USB 2.0 Eye Diagram with USB Switch

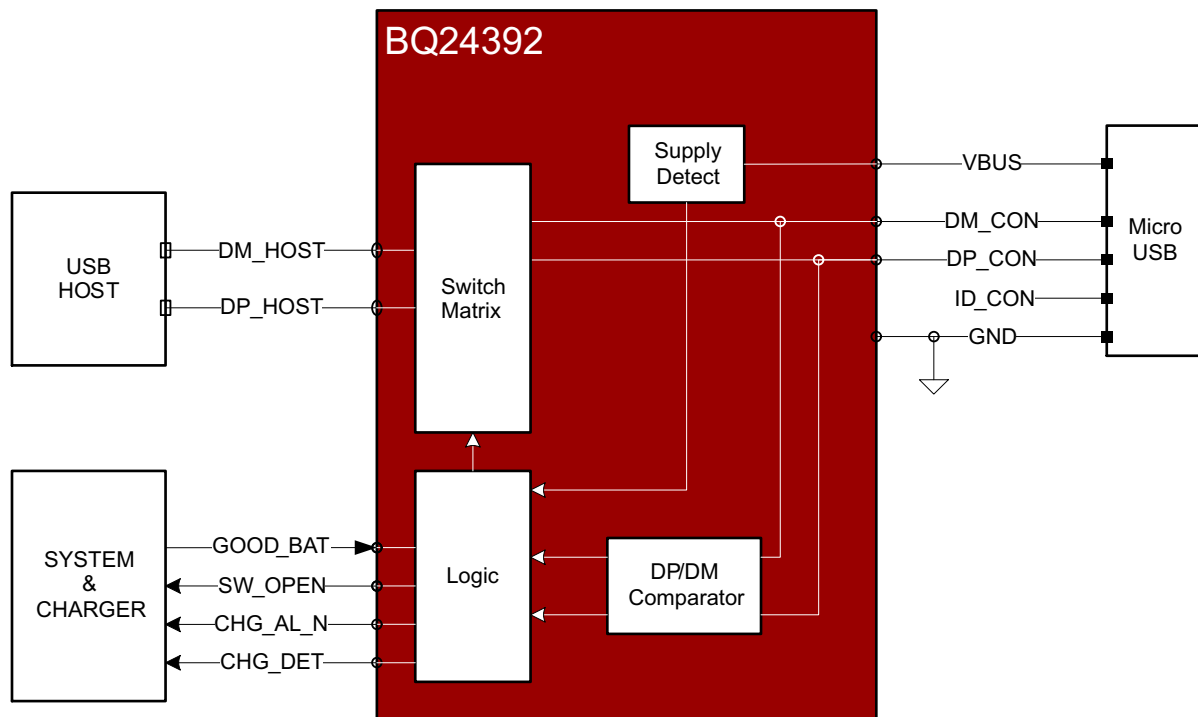
7 Detailed Description

7.1 Overview

The BQ24392-Q1 is a USB 2.0 high-speed isolation switch with charger detection capabilities for use with micro and mini-USB ports. Upon plugin of a Battery Charging Specification 1.2 (BCv1.2) compliant, Apple™, TomTom™, or other USB charger into a micro or mini-USB connector, the device will automatically detect the charger and operate the USB 2.0 high-speed isolation switch.

The BQ24392-Q1 device is powered through VBUS when a charger is attached to the micro or mini-USB port and has a 28-V tolerance to avoid the need for external protection.

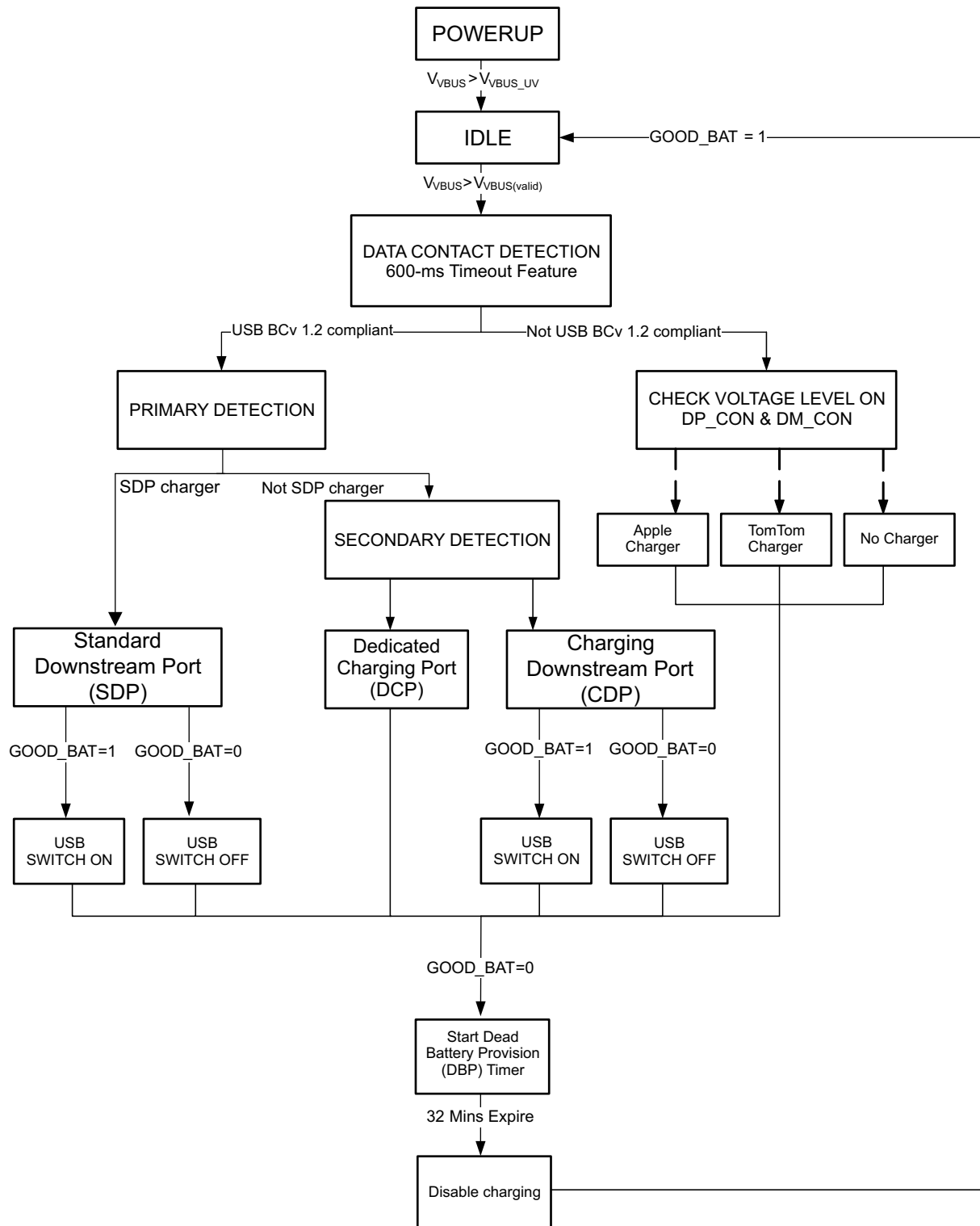
7.2 Functional Block Diagram



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7.3 Feature Description

7.3.1 Charger Detection



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Figure 3. Logic Tree

Feature Description (continued)

When a micro or mini-USB accessory is inserted into the connector and once VVBUS is greater than V_{VBUS_VALID} threshold, the BQ24392-Q1 will enter into the Data Contact Detection (DCD) state which includes a 600-ms timeout feature that is prescribed in the USB Battery Charging Specification version 1.2 (BCv1.2). If the micro or mini-USB accessory is determined to be USB BCv1.2 compliant, a 130-ms debounce period will initiate and the BQ24392-Q1 will proceed to its primary detection and then secondary detection states to determine if a Dedicated Charging Port (DCP), Standard Downstream Port (SDP), or Charging Downstream Port (CDP) is attached to the USB-port. The minimum detection time for a DCP, SDP, and CDP is 130 ms, but can be as long as 600 ms due to the slow plug in effect.

If the GOOD_BAT pin is high, the USB 2.0 switches are automatically closed to enable data transfer after the device detects a Standard Downstream Port (SDP) or Charging Downstream Port (CDP) was connected.

If Data Contact Detection (DCD) fails, the BQ24392-Q1 proceeds to detect whether an Apple or TomTom charger was inserted by checking the voltage level on DP_CON and DM_CON. Thus, for Apple and TomTom chargers, detection time typically takes ~600 ms.

The 3 output pins CHG_AL_N, CHG_DET, and SW_OPEN change their status at the end of detection. [Table 1](#) is the detection table with the GPIO status for each type of supported charger. More information on how to use the GPIOs is available in [Using the BQ24392-Q1 GPIOs](#).

Table 1. Detection Table

| Device Type | VBUS | DP_CON (D+) | DM_CON (D-) | GOOD_BAT (Input) | CHG_AL_N (Output) | CHG_DET (Output) | SW_OPEN (Output) | Switch Status | Charge Current |
|------------------------------|---------|---|---|------------------|-------------------|------------------|------------------|---------------|--|
| Standard Downstream Port | > 3.5 V | Pull-down R to GND | Pull-down R to GND | HIGH | LOW | LOW | LOW | Connected | Charge with 100mA/ Change the input current based on enumeration |
| | | | | LOW | LOW | LOW | High-Z | Not Connected | Charge with 100 mA |
| Charging Downstream Port | > 3.5 V | Pull-down R to GND | V_{DM_SRC} | HIGH | LOW | HIGH | LOW | Connected | Charge with full current |
| | | | | LOW | LOW | HIGH | High-Z | Not Connected | Charge with 100 mA |
| Dedicated Charging Port | > 3.5 V | Short to D- | Short to D+ | X | LOW | HIGH | High-Z | Not Connected | Charge with full current |
| Apple Charger | > 3.5 V | $2.0\text{ V} < V_{DP_CON} < 2.8\text{ V}$ | $2.0\text{ V} < V_{DM_CON} < 2.8\text{ V}$ | X | LOW | HIGH | High-Z | Not Connected | Charge with full current |
| TomTom Charger | > 3.5 V | $2.0\text{ V} < V_{DP_CON} < 3.1\text{ V}$ | $2.0\text{ V} < V_{DM_CON} < 3.1\text{ V}$ | X | LOW | HIGH | High-Z | Not Connected | Charge with full current |
| PS/2 Charger | > 3.5 V | Pull-up R to V_{VBUS} | Pull-up R to V_{VBUS} | X | LOW | LOW | High-Z | Not Connected | Charge with 100 mA |
| Non-compliant USB Charger | > 3.5 V | Open | Open | X | LOW | LOW | High-Z | Not Connected | Charge with 100 mA |
| Any Device | < 3.5 V | Open | Open | X | High-Z | LOW | High-Z | Not Connected | No Charge |
| Any Device DBP Timer Expired | > 3.5 V | X | X | LOW | High-Z | LOW | High-Z | Not Connected | No Charge |

If a charger has been detected and the GOOD_BAT pin is low, a Dead Battery Provision (DBP) timer is initiated. If the GOOD_BAT continues to be low for 30 minutes (maximum of 45 minutes), charging is disabled and CHG_AL_N goes into the High-Z state to indicate this. Toggling GOOD_BAT high after the DBP timer expires re-starts detection and the DBP timer.

7.4 Device Functional Modes

The BQ24392-Q1 has three functional modes:

1. Nothing inserted
2. Accessory inserted and detection running
3. Accessory inserted and detected

8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

8.1.1 Using the BQ24392-Q1 GPIOs

8.1.1.1 CHG_AL and CHG_DET

The BQ24392-Q1 has 2 charger indicators, CHG_AL_N and CHG_DET, that the host can use to determine whether it can charge and if it can charge at a low or high current. [Table 2](#) demonstrates how these outputs should be interpreted. CHG_AL_N is an open drain output and is active when the output of the pin is low. CHG_DET is a push-pull output and is high in the active state.

Table 2. BQ24392-Q1 Outputs

| CHG_AL_N | CHG_DET | |
|----------|---------|----------------------------------|
| High-Z | X | Charging is not allowed |
| Low | Low | Low-current charging is allowed |
| Low | High | High-current charging is allowed |

The system must define what is meant by low-current and high-current charging. If CHG_DET is high, a system could try to draw 2 A, 1.5 A, or 1.0 A. If the system is trying to support greater than 1.5-A chargers, then the system has to use a charger IC that is capable of monitoring the VBUS voltage as it tries to pull the higher current values. If the voltage on VBUS starts to drop because that high of a current is supported then the system has to reduce the amount of current it is trying to draw until it finds a stable state with VBUS not dropping.

8.1.1.2 SW_OPEN

SW_OPEN is an open drain output that indicates whether the USB switches are opened or closed. In the High-Z state the switches are open and in the active, or low state, the switches are closed. The host should monitor this pin to know when the switches are closed or open.

8.1.1.3 GOOD_BAT

GOOD_BAT is used by the host controller to indicate the status of the battery to the BQ24392-Q1. This pin affects the switch status for a SDP or CDP, and it also affects the Dead Battery Provision (DBP) timer as discussed in the [Charger Detection](#) section.

8.1.1.4 Slow Plug-in Event

As you insert a charger into the USB receptacle, the pins are configured so that the VBUS and GND pins make contact first. This presents a problem as the BQ24392-Q1 (or any other charger detection IC) requires access to the D+ and D– lines to run detection. This is why the BQ24392-Q1 has a standard 130-ms debounce time after VBUS valid to run the detection algorithm. This delay helps minimize the effects of the D+ and D– lines making contact after VBUS and GND.

[Figure 4](#) is from the datasheet of a standard male micro-USB connector and shows how the data connections (red line) are slightly recessed from the power connections (blue line).

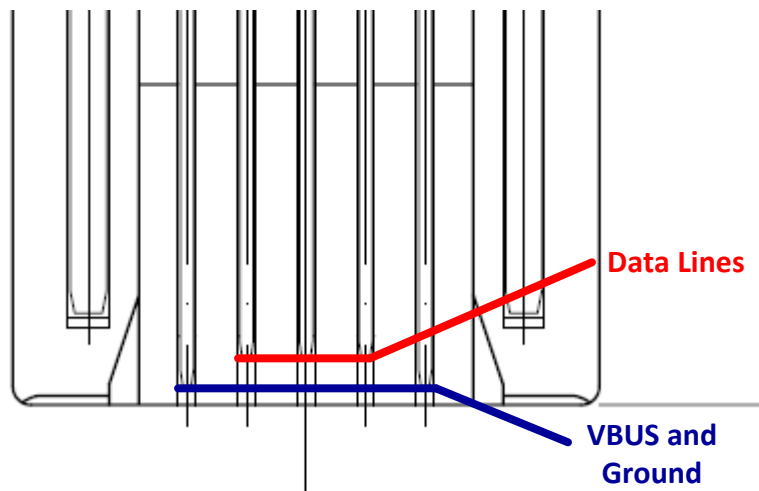
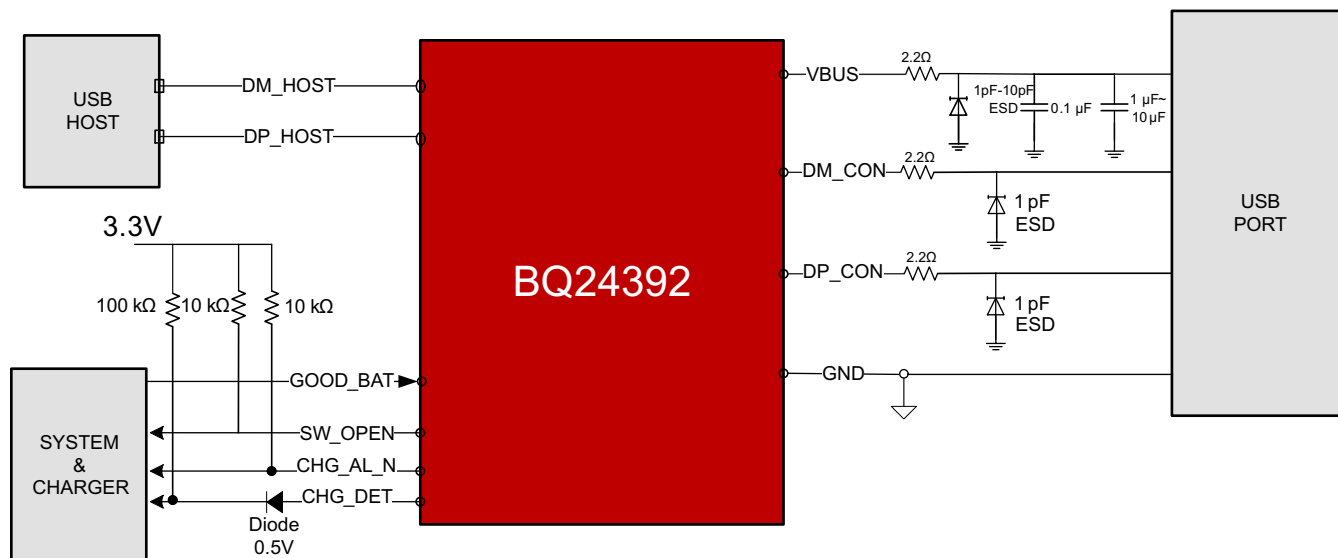


Figure 4. Data Connections Recessed from Power Connections

However, in some cases the charger is inserted very slowly, causing the VBUS and GND to make contact long before D+ and D-. Due to this effect, there is no guaranteed detection time as the detection time can vary based on how long it takes the user to insert the charger. If insertion takes longer than 600 ms, the detection algorithm of the BQ24392-Q1 will timeout and detect the charger as a non-standard charger.

8.2 Typical Application

The BQ24392-Q1 device is used between the micro or mini-USB connector port and USB host to enable and disable the USB data path and detect chargers that are inserted into the micro or mini-USB connector.



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Figure 5. Application Schematic

Typical Application (continued)

8.2.1 Design Requirements

VBUS requires 1-μF – 10-μF and 0.1-μF bypass capacitors to reduce noise from circuit elements by providing a low impedance path to ground for the unwanted high frequency content. The 0.1-μF capacitor filters out higher frequencies and has a lower series inductance while the 1 μF ~ 10 μF capacitor filters out the lower frequencies and has a much higher series inductance. Using both capacitors will provide better load regulation across the frequency spectrum.

SW_OPEN and CHG_AL_N are open-drain outputs that require a 10-kΩ pull-up resistor to VDDIO and VBUS.

VBUS, DM_CON, and DP_CON are recommended to have an external resistor of 2.2 Ω to provide extra ballasting to protect the chip and internal circuitry.

DM_CON and DP_CON are recommended to have a 1-pF external ESD protection diode rated for 8-kV IEC protection to prevent failure in case of an 8-kV IEC contact discharge.

VBUS is recommended to have a 1-pF ~ 10-pF external ESD Protection Diode rated for 8-kV IEC protection to prevent failure in case of an 8-kV IEC contact discharge

CHG_DET is a push-pull output pin. An external pull-up and diode are shown to depict a typical 3.3-V system. The pull-up resistor and diode are optional. The pull-up range on the CHG_DET pin is from 3.5 V to V_{VBUS}. When V_{VBUS} > 7 V, CHG_DET will be clamped to 7 V.

8.2.2 Detailed Design Procedure

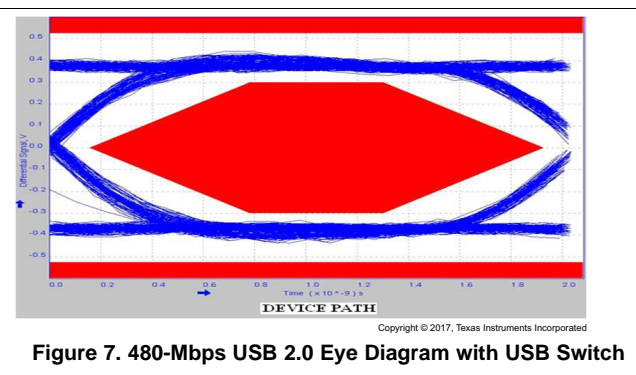
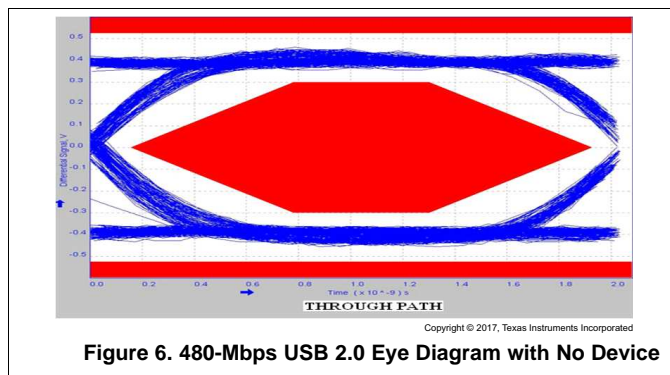
The minimum pull-up resistance for the open-drain data lines is a function of the pull-up voltage V_{PU}, output logic LOW voltage V_{OL(max)}, and Output logic LOW current I_{OL}.

$$R_{PU(MIN)} = (V_{PU} - V_{OL(MAX)}) / I_{OL} \quad (1)$$

The maximum pull-up resistance for the open-drain data lines is a function of the maximum rise time of the desired signal, t_r, and the bus capacitance, C_b.

$$R_{PU(MAX)} = t_r / (0.8473 \times C_b) \quad (2)$$

8.2.3 Application Curves



9 Power Supply Recommendations

Power to the device is supplied through the VBUS pin from the device that is inserted into the mini or micro-USB port. The power from the inserted devices should follow BCv1.2 specification.

10 Layout

10.1 Layout Guidelines

Place VBUS bypass capacitors as close to VBUS pin as possible and avoid placing the bypass caps near the DP/DM traces.

The high speed DP/DM traces should always be matched lengths and must be no more than 4 inches; otherwise, the eye diagram performance may be degraded. A high-speed USB connection is made through a shielded, twisted pair cable with a differential characteristic impedance of $90\ \Omega \pm 15\%$. In layout, the impedance of DP and DM traces should match the cable characteristic differential $90\text{-}\Omega$ impedance.

Route the high-speed USB signals using a minimum of vias and corners. This reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points on twisted pair lines; through-hole pins are not recommended.

When it becomes necessary to turn 90° , use two 45° turns or an arc instead of making a single 90° turn. This reduces reflections on the signal traces by minimizing impedance discontinuities.

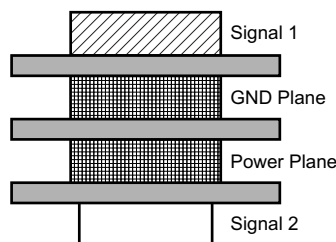
Do not route USB traces under or near crystals, oscillators, clock signal generators, switching regulators, mounting holes, magnetic devices or IC's that use or duplicate clock signals.

Avoid stubs on the high-speed USB signals because they cause signal reflections. If a stub is unavoidable, then the stub should be less than 200 mm.

Route all high-speed USB signal traces over continuous planes (VCC or GND), with no interruptions.

Avoid crossing over anti-etch, commonly found with plane splits.

Due to high frequencies associated with the USB, a printed circuit board with at least four layers is recommended; two signal layers separated by a ground and power layer as shown in [Figure 8](#).



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Figure 8. Four-Layer Board Stack-Up

The majority of signal traces should run on a single layer, preferably Signal 1. Immediately next to this layer should be the GND plane, which is solid with no cuts. Avoid running signal traces across a split in the ground or power plane. When running across split planes is unavoidable, sufficient decoupling must be used. Minimizing the number of signal vias reduces EMI by reducing inductance at high frequencies.

10.2 Layout Example

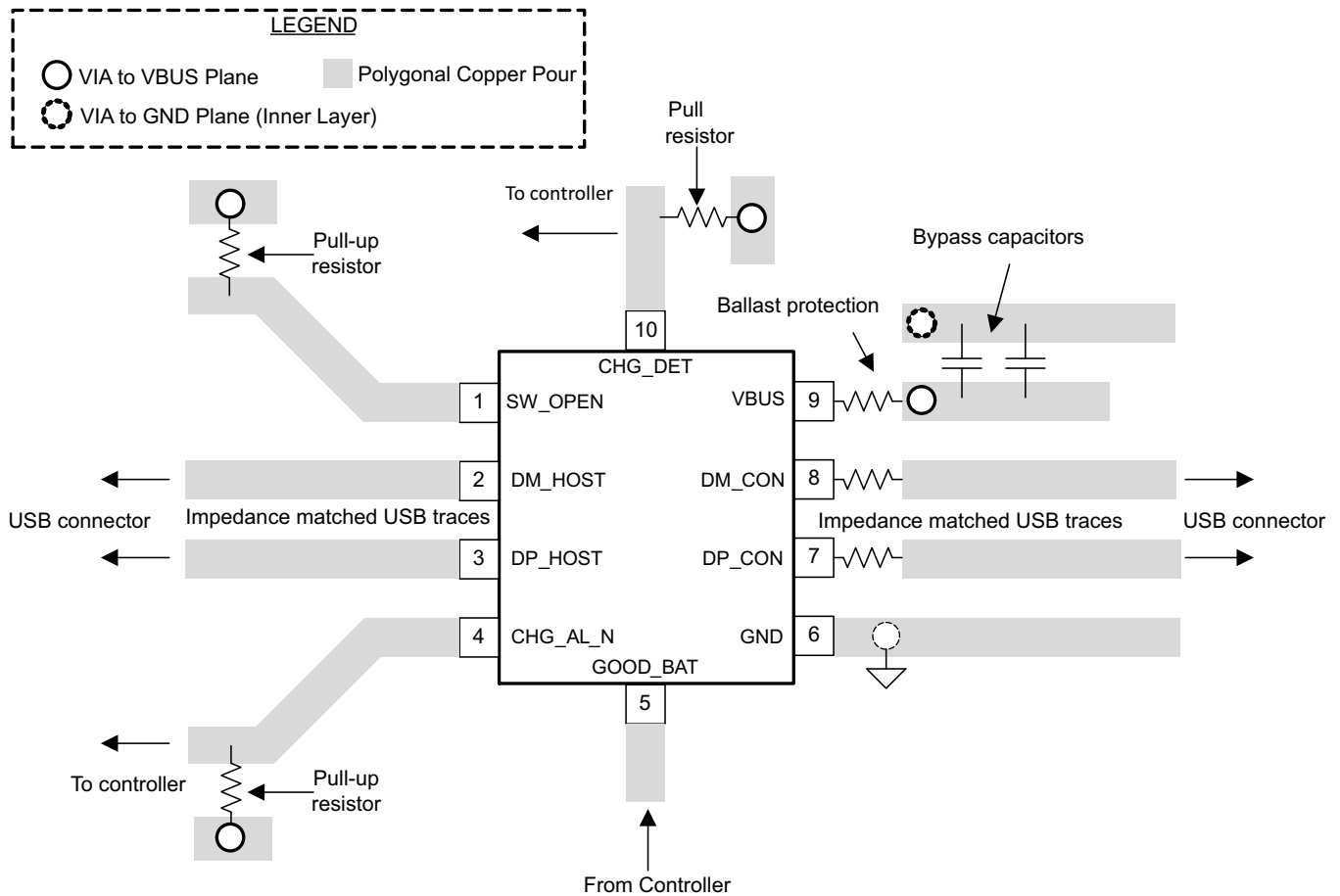


Figure 9. Package Layout

11 器件和文档支持

11.1 社区资源

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

TI E2E™ Online Community *TI's Engineer-to-Engineer (E2E) Community*. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.2 商标

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11.3 静电放电警告



这些装置包含有限的内置 ESD 保护。存储或装卸时，应将导线一起截短或将装置放置于导电泡棉中，以防止 MOS 门极遭受静电损伤。

11.4 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 机械、封装和可订购信息

以下页中包括机械、封装和可订购信息。这些信息是针对指定器件可提供的最新数据。这些数据会在无通知且不对本文档进行修订的情况下发生改变。欲获得该数据表的浏览器版本，请查阅左侧的导航栏。

PACKAGING INFORMATION

| Orderable part number | Status (1) | Material type (2) | Package Pins | Package qty Carrier | RoHS (3) | Lead finish/ Ball material (4) | MSL rating/ Peak reflow (5) | Op temp (°C) | Part marking (6) |
|--------------------------------|---------------|----------------------|-----------------|-----------------------|-------------|--------------------------------------|-----------------------------------|--------------|---------------------|
| BQ24392QRSERQ1 | Active | Production | UQFN (RSE) 10 | 3000 LARGE T&R | Yes | NIPDAUAG | Level-3-260C-168 HR | -40 to 125 | EXH |
| BQ24392QRSERQ1.B | Active | Production | UQFN (RSE) 10 | 3000 LARGE T&R | Yes | NIPDAUAG | Level-3-260C-168 HR | -40 to 125 | EXH |

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF BQ24392-Q1 :

- Catalog : [BQ24392](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

TAPE AND REEL INFORMATION


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|----------------|--------------|-----------------|------|------|--------------------|--------------------|---------|---------|---------|---------|--------|---------------|
| BQ24392QRSERQ1 | UQFN | RSE | 10 | 3000 | 180.0 | 8.4 | 1.68 | 2.13 | 0.76 | 4.0 | 8.0 | Q1 |

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

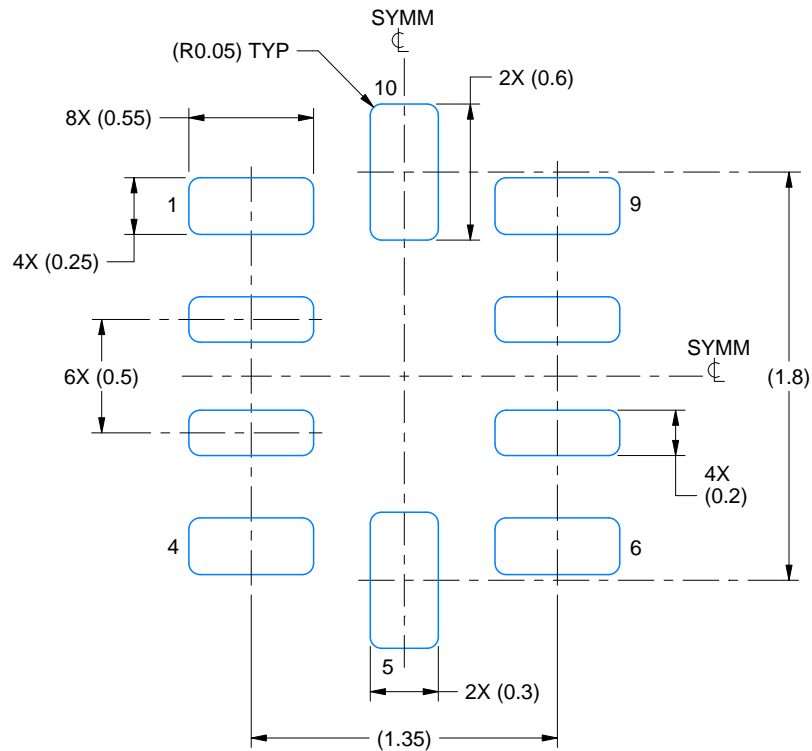
| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|----------------|--------------|-----------------|------|------|-------------|------------|-------------|
| BQ24392QRSERQ1 | UQFN | RSE | 10 | 3000 | 223.0 | 270.0 | 35.0 |

EXAMPLE BOARD LAYOUT

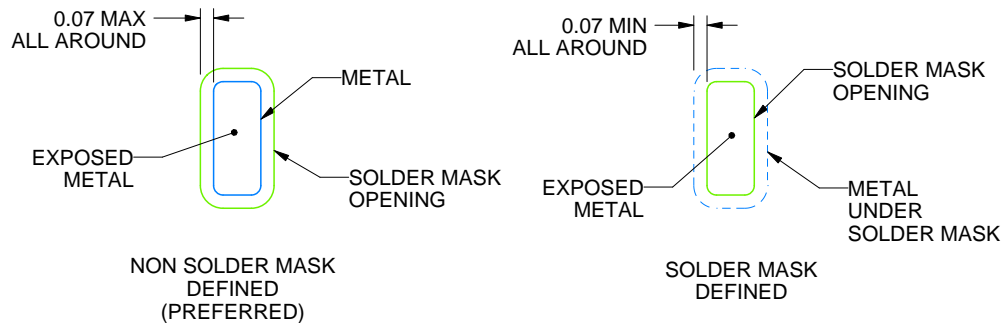
RSE0010A

UQFN - 0.6 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:30X



SOLDER MASK DETAILS
NOT TO SCALE

4220307/A 03/2020

NOTES: (continued)

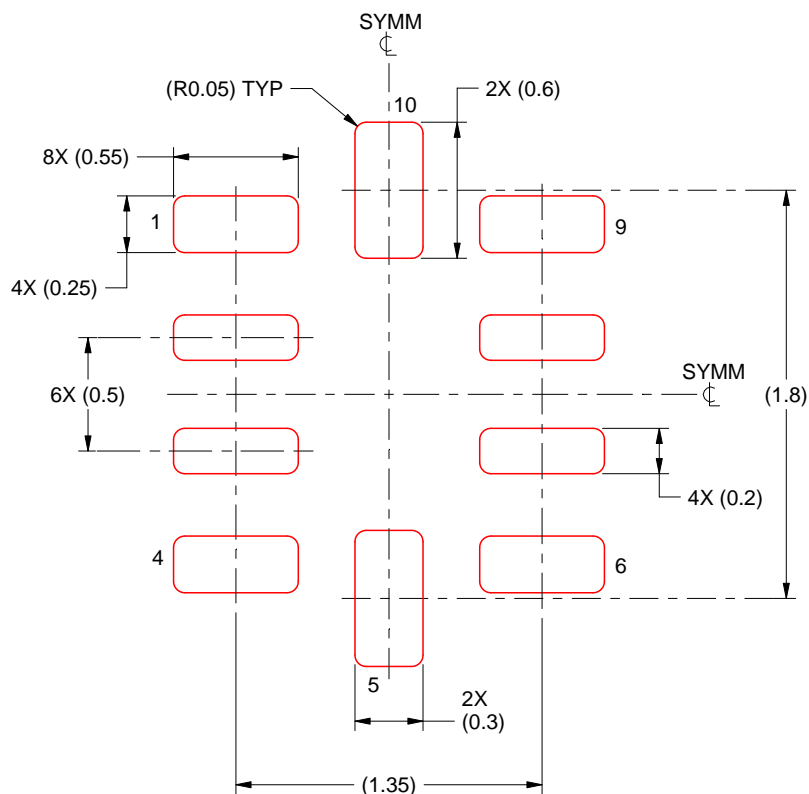
3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

EXAMPLE STENCIL DESIGN

RSE0010A

UQFN - 0.6 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



SOLDER PASTE EXAMPLE
BASED ON 0.1 mm THICKNESS
SCALE: 30X

4220307/A 03/2020

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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